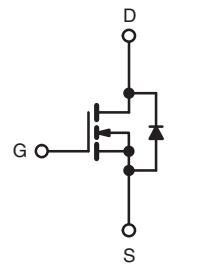
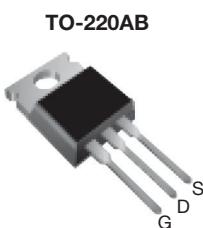


Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	950
R _{DSD(on)} (Ω)	V _{GS} = 10 V 5.0
Q _g (Max.) (nC)	80
Q _{gs} (nC)	10
Q _{gd} (nC)	42
Configuration	Single

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	950	V	
Gate-Source Voltage		V _{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	I _D	A	
		T _C = 100 °C	2.0		
Pulsed Drain Current ^a		I _{DM}	12		
Linear Derating Factor			1.0	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	280	mJ	
Repetitive Avalanche Current ^a		I _{AR}	3.1	A	
Repetitive Avalanche Energy ^a		E _{AR}	13	mJ	
Maximum Power Dissipation	T _C = 25 °C	P _D	125	W	
Peak Diode Recovery dV/dt ^c		dV/dt	1.0	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)			300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf · in	
			1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 50 V, starting T_J = 25 °C, L = 55 mH, R_g = 25 Ω, I_{AS} = 3.1 A (see fig. 12).

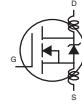
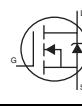
c. I_{SD} ≤ 3.1 A, dI/dt ≤ 80 A/μs, V_{DD} ≤ 600, T_J ≤ 150 °C.

d. 1.6 mm from case.

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.0	

SPECIFICATIONS ($T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	950	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}$	-	1.4	-	$\text{V}/^{\circ}\text{C}$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.0	-	4.0	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 1000 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	100	μA
		$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125 \text{ }^{\circ}\text{C}$	-	-	500	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 1.9 \text{ A}^b$	-	5.0	-
Forward Transconductance	g_{fs}	$V_{DS} = 10 \text{ V}$	$I_D = 1.9 \text{ A}^b$	2.1	-	-
Dynamic						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz, see fig. 5}$	-	980	-	pF
Output Capacitance	C_{oss}		-	140	-	
Reverse Transfer Capacitance	C_{rss}		-	50	-	
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 3.1 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	80
Gate-Source Charge	Q_{gs}			-	-	10
Gate-Drain Charge	Q_{gd}			-	-	42
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 500 \text{ V}, I_D = 3.1 \text{ A}$	$R_g = 12 \Omega, R_D = 170 \Omega, \text{ see fig. 10}^b$	-	12	-
Rise Time	t_r			-	25	-
Turn-Off Delay Time	$t_{d(off)}$			-	89	-
Fall Time	t_f			-	29	-
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-
Internal Source Inductance	L_S			-	7.5	-
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	3.1
Pulsed Diode Forward Current ^a	I_{SM}			-	-	12
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}, I_S = 3.1 \text{ A}, V_{GS} = 0 \text{ V}^b$	-	-	1.8	V
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}, I_F = 3.1 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^b$	-	410	620	ns
Body Diode Reverse Recovery Charge	Q_{rr}		-	1.3	2.0	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2 \%$.

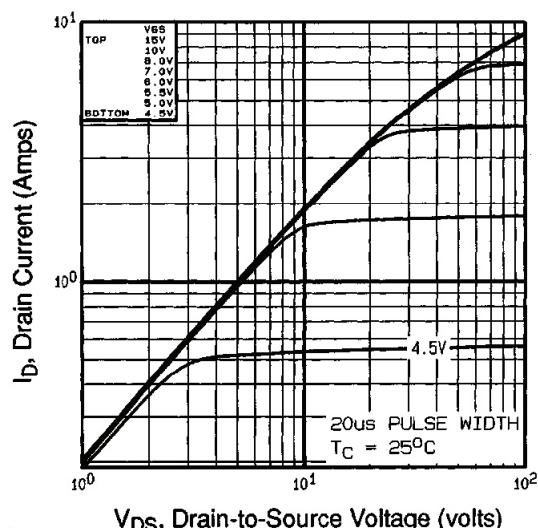
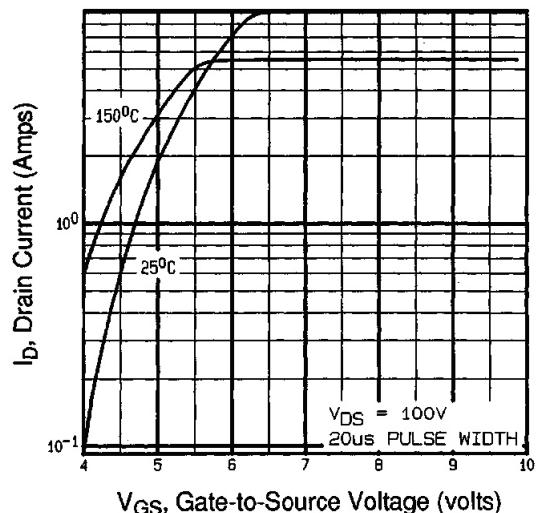
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)
Fig. 1 - Typical Output Characteristics, $T_C = 25^{\circ}\text{C}$ 

Fig. 3 - Typical Transfer Characteristics

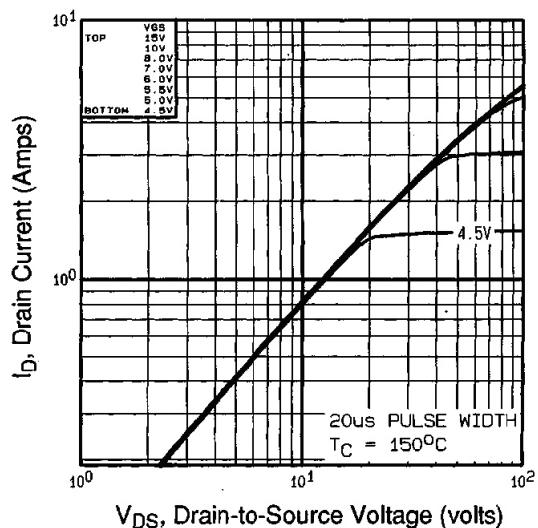
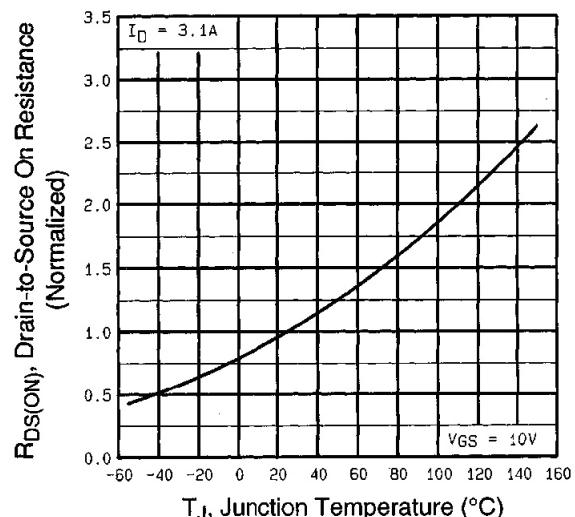
Fig. 2 - Typical Output Characteristics, $T_C = 150^{\circ}\text{C}$ 

Fig. 4 - Normalized On-Resistance vs. Temperature

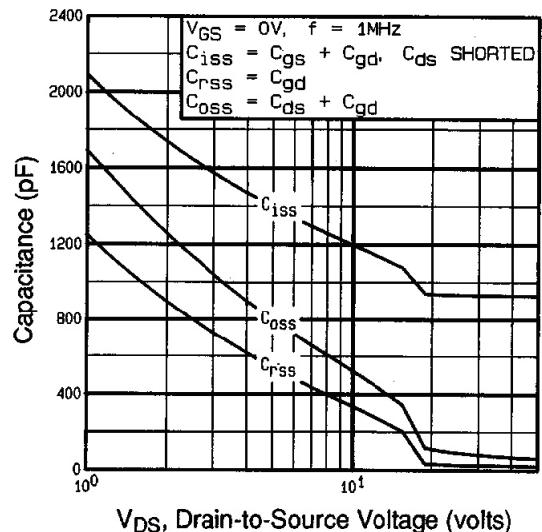


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

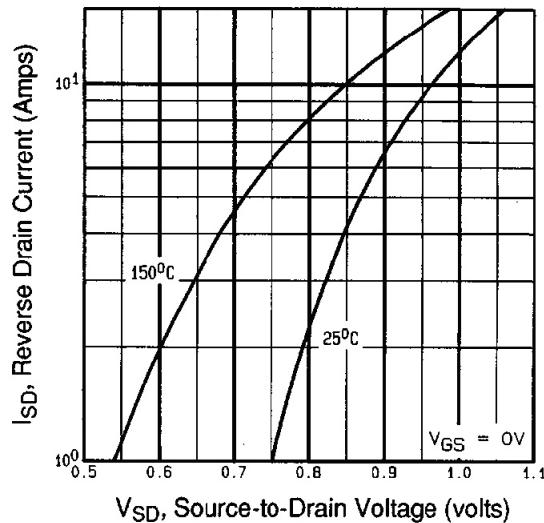


Fig. 7 - Typical Source-Drain Diode Forward Voltage

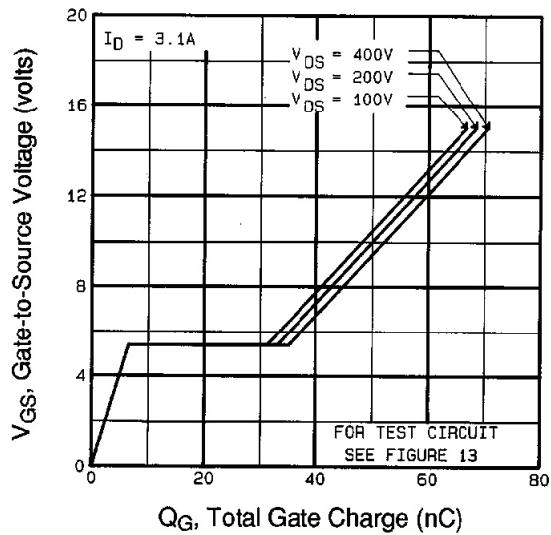


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

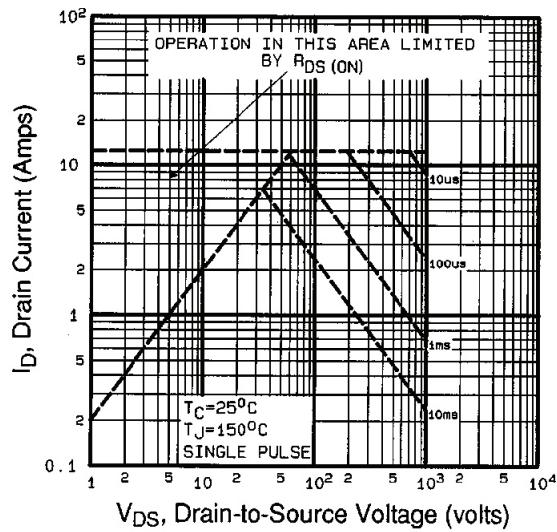


Fig. 8 - Maximum Safe Operating Area

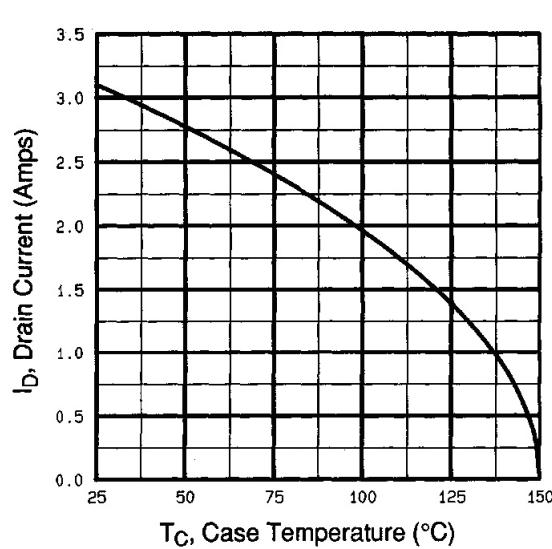


Fig. 9 - Maximum Drain Current vs. Case Temperature

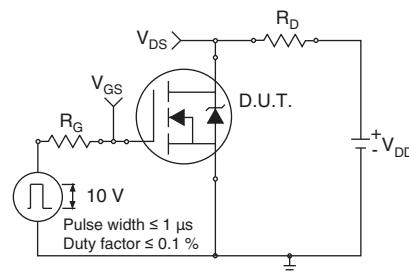


Fig. 10a - Switching Time Test Circuit

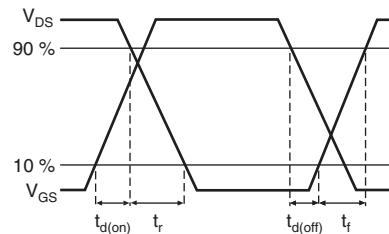


Fig. 10b - Switching Time Waveforms

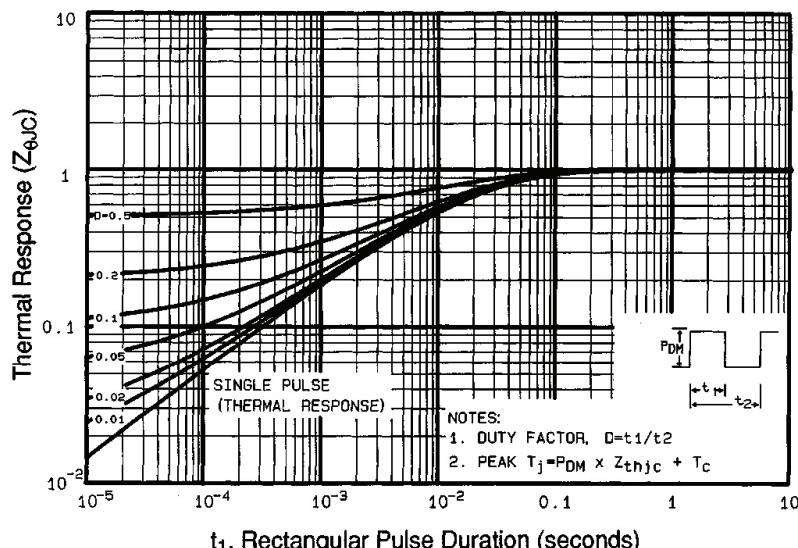


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

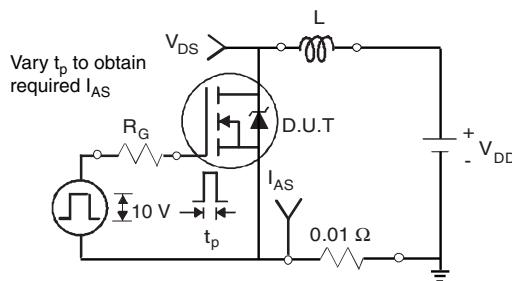


Fig. 12a - Unclamped Inductive Test Circuit

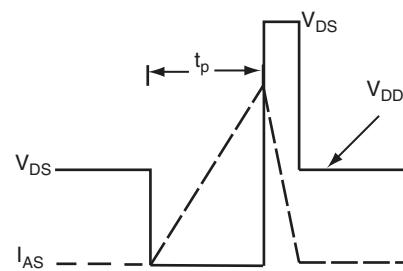


Fig. 12b - Unclamped Inductive Waveforms

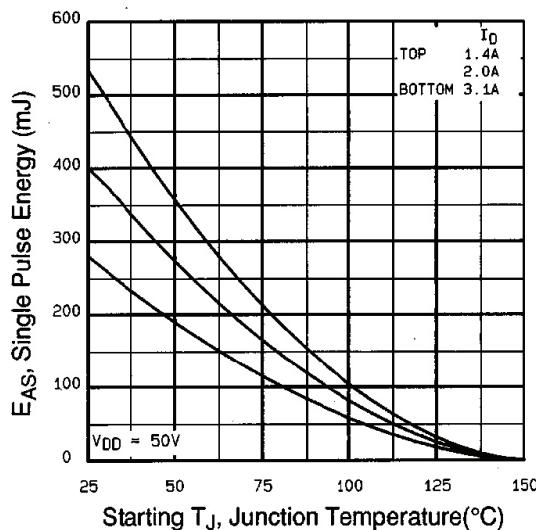


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

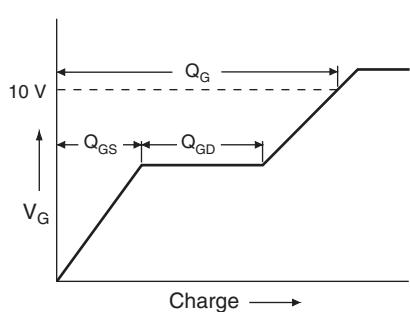


Fig. 13a - Basic Gate Charge Waveform

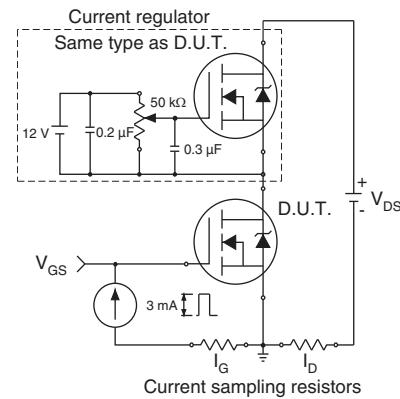
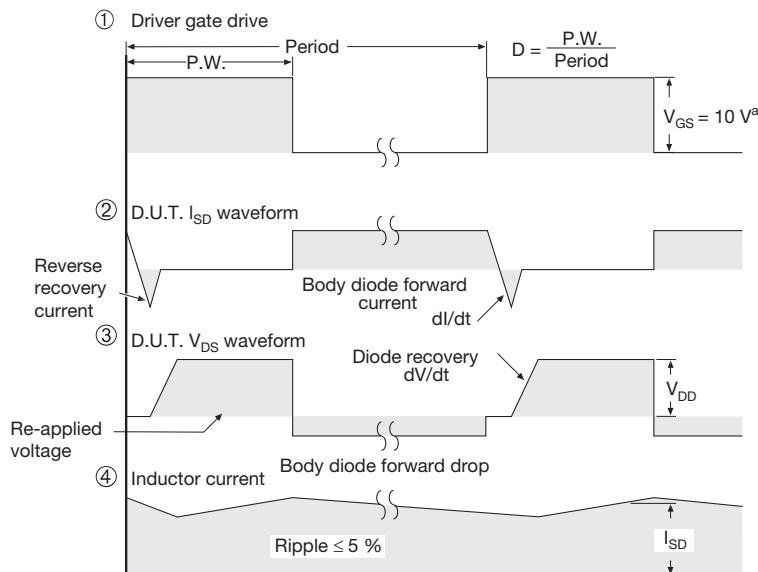
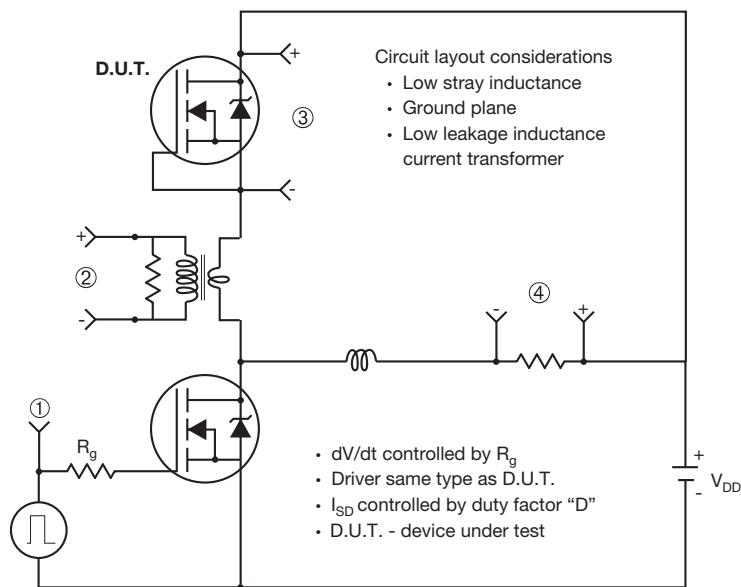
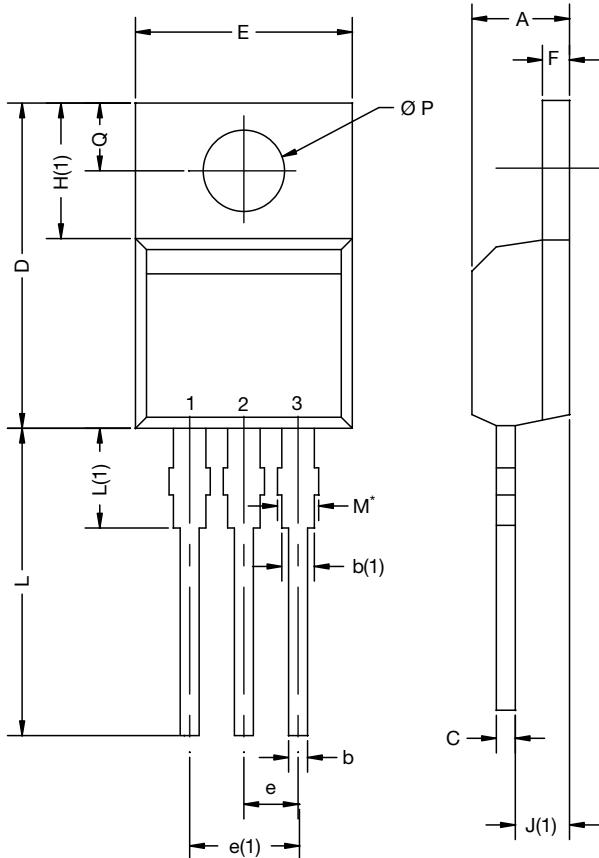


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit
**Note**a. $V_{GS} = 5$ V for logic level devices**Fig. 14 - For N-Channel**

TO-220-1

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.24	4.65	0.167	0.183
b	0.69	1.02	0.027	0.040
b(1)	1.14	1.78	0.045	0.070
c	0.36	0.61	0.014	0.024
D	14.33	15.85	0.564	0.624
E	9.96	10.52	0.392	0.414
e	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.10	6.71	0.240	0.264
J(1)	2.41	2.92	0.095	0.115
L	13.36	14.40	0.526	0.567
L(1)	3.33	4.04	0.131	0.159
Ø P	3.53	3.94	0.139	0.155
Q	2.54	3.00	0.100	0.118

ECN: X15-0364-Rev. C, 14-Dec-15
DWG: 6031

Note

- M* = 0.052 inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM

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